

USPTO
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. 30-5004 DIV3		PRIORITY SERIAL NO. 09/465,492	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Vladimir Segal et al.			
					PRIORITY FILING DATE December 16, 1999		PRIORITY GROUP 1742	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
HW	AA	4,619,695	10/1986	Oikawa et al.	75	65EB		
HW	AB	5,400,633	03/1995	Segal et al.	72	272		
HW	AC	5,513,512	05/1996	Segal	72	253.1		
HW	AD	5,590,389	12/1996	Dunlop et al.	419	67		
HW	AE	5,600,989	02/1997	Segal et al.	72	253.1		
HW	AF	5,673,581	10/1997	Setal	72	184		
HW	AG	4,663,120	05/1987	Parent et al.	—	—		
HW	AH	4,762,558	08/1988	German et al.	—	—		
HW	AI	4,889,745	12/1989	Sata	—	—		
HW	AJ	5,330,701	07/1994	Shaw et al.	—	—		
HW	AK	5,418,071	05/1995	Satou et al.	—	—		
HW	AL	5,508,000	04/1996	Satou et al.	—	—		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
HW	AM	590904	04/1994	EP	C23C	14/34		
HW	AN	9201080	01/1992	PCT	C23C	14/35		
HW	AO	610107	01/1994	Japan (*transl. of Abst)	C22	18	X*	
HW	AP	693400	04/1994	Japan (*transl. of Abst)	C22	18	X*	
HW	AQ	6256919	09/1994	Japan (*transl. of Abst)	C22	18	X*	
OTHER REFERENCES (including Author, Title; Date; Pertinent Pages, Etc.)								
HW	AR		C. Klein et al., "Manual of Mineralogy", pp 39-40					
HW	AS		S. Wright et al. "Effect of Annealing Temperature on the Texture of Rolled Tantalum and Tantulum-10 Wt.% Tungsten, reprinted from Tungsten and Refractory Metals 2, pp 501-508					
HW	AT		H-R Wenk, "Preferred Orientation in Deformed Metals and Rocks: An Introduction to Modern Texture Analysis", 1985, pp 8-10					
EXAMINER	<i>Mary J. S. Smith</i>			DATE CONSIDERED		8/7/02		
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<i>JAW</i>	AA	5,608,911	03/1997	Shaw et al.					
<i>KW</i>	AB	5,772,860	06/1998	Sawada et al.					
<i>KW</i>	AC	5,993,621	11/1999	Liu					
<i>KW</i>	AD	5,798,005	08/1998	Murata et al.					
<i>KW</i>	AE	5,282,946	02/1994	Kinoshita et al.					
<i>JAW</i>	AF	5,993,575	11/1999	Lo et al.					
<i>JW</i>	AG	5,809,393	09/1998	Dunlop et al.					
<i>KW</i>	AH	5,468,401	11/1995	Lum et al.					
<i>KW</i>	AI	5,087,297	02/1992	Pouliquen					
<i>KW</i>	AJ	5,693,203	12/1997	Ohhashi et al.					
<i>JW</i>	AK	5,074,907	12/1991	Amato et al.					
<i>JW</i>	AL	4,525,417	06/1985	Dimigen et al.					
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country	Class	Subclass	Translation		
							Yes	No	
<i>JW</i>	AM	8-100255	04/1996	Japan			X		
<i>JW</i>	AN	8-64554	03/1996	Japan			X		
<i>JW</i>	AO	06264232	09/1994	Japan			X		
<i>JW</i>	AP	WO 00/31310	06/2000	PCT					
<i>JW</i>	AQ	7-90566	04/1995	JAPAN			X		
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
<i>JW</i>	AR	B.D. Cullity, "Structure of Polycrystalline Aggregates", <u>Elements of X-ray Diffraction</u> , pp 294-297							
	AS								
	AT								
EXAMINER	<i>Vladimir Segal</i>		DATE CONSIDERED <i>8/7/02</i>						

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U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	SN 09/098,760 As filed and Amended		Shah et al.			6/17/98	
HW	AB	4,842,706	06/1989	Fukasawa et al.				
HW	AC	4,960,163	10/1990	Fang et al.	← →			
HW	AD	5,780,755	07/1998	Dunlop et al.	→			
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
HW	AM	08269701	10/1996	Japan	→		X	
HW	AN	08232061	06/1996	Japan	→		X	
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
HW	AR		B.D. Cullity, "Structure of Polycrystalline Aggregates", <u>Elements of X-ray Diffraction</u> , pp 294-297					
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	AT							
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. 30-5004DIV3	RECEIVED SERIAL NO. 09/912,616		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vladimir Segal	APR 15 2002		
				FILING DATE July 24, 2001	GROUP 1742 FC 1700		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HW	AA	5,850,755	12/98	Segal			
HW	AB	5,456,815	10/95	Fukuyo et al.			
HW	AC	5,826,456	10/98	Kawazoe et al.			
HW	AD	5,413,650	5/95	Jarrett et al.			
HW	AE	6,193,821 B1	2/01	Zhang			
HW	AF	6,348,113 B1	2/02	Michaluk et al.			
HW	AG	6,085,966	7/00	Shimomuki et al.			
HW	AH	6,024,852	2/00	Tamura et al.			
HW	AI	5,798,005	08/98	Murata et al.			
HW	AJ	5,231,306	07/93	Meikle et al.			
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
HW	AM	WO 99/66100	23.12.1999	PCT			
HW	AN	WO 87/07650	17.12.1987	PCT			
HW	AO	0 882 813 A1	09.12.1998	EPO			
HW	AP	08146201	07.06.1996	Japan			
HW	AQ	10008244	13.01.1998	Japan			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AR	Mukai et al., "Dynamic Mechanical Properties of a Near-Nano Aluminum Alloy Processed by Equal-Channel-Abular-Extrusion", 1998, pp. 755-765, NanoStructured Materials, Vol. 10, No. 5					
HW	AS	Ferrasse, S. et al., "Development of a Submicrometer-Grained Microstructure in Aluminum 6061 Using Equal Channel Angular Extrusion", J. Mater. Res. Vol. 12, No. 5, May 1997, pp. 1253-1261.					
HW	AT	Ferrasse, S. et al., "Microstructure and Properties of Copper and Aluminum Alloy 3003 Heavily Worked by Equal Channel Angular Extrusion", Metallurgical and Materials Transactions A, vol. 28A, April 1997, pp. 1047-1057.					
EXAMINER				DATE CONSIDERED			
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass		
	AA	APR 04 2001 PATENT & TRADEMARK OFFICE		RECEIVED	Filing Date If Appropriate		
	AB			APR 15 2002			
	AC			TC 1700			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
				Yes	No		
HW	AM WO 99/27150	03.06.1999	PCT				
HW	AN WO 99/02743	21.01.1999	PCT				
HW	AO WO 01/29279 A1	26.04.2001	PCT				
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AR	Pavate et al., "Correlation between Aluminum alloy sputtering target metallurgical characteristics, Arc initiation, and In-film defect density", SPIE Vol. 3214, 1997, pp. 42-47.					
HW	AS	Hatch, J.E., <u>ALUMINUM</u> , 1984, Chap. 5, "Metallurgy of Heat Treatment and General Principles of Precipitation Heating", pp. 134-157, 175-183.					
	AT						
EXAMINER	<i>Henry S. Wilkins Jr.</i>			DATE CONSIDERED	8/7/02		
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